



EV372467541

Sheet 1 of 1

Form PTO-1419		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M140-273		SERIAL NO. 09/502,693	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.		FILING DATE February 11, 2000	
				GROUP 3684			
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AL	0 172 445 A1	07/1985	EPO (Statement of Relevance provided in IDS)			x
	AM	0 682 382 A2	04/1995	EPO (Statement of Relevance provided in IDS)			x
	AN	0 682 382 A3	05/1995	EPO (Statement of Relevance provided in IDS)			x
	AO						
	AP						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR						
	AS						
	AT						
EXAMINER				DATE CONSIDERED			
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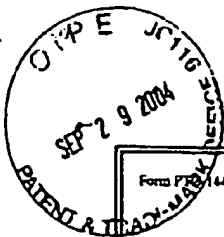


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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M140-273		SERIAL NO. 09502.693	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.			
				FILING DATE February 11, 2000		GROUP 3662	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	5,361,403	11/1994	Deui	455	74	
	AB	5,423,074	06/1995	Deui	455	74	
	AC	4,783,646	11/1988	Matsuaki	340	572	
	AD	5,072,194	12/1991	Chevallier	330	260	
	AE	5,300,596	04/1994	Soesterman	330	260	
	AF	5,365,192	11/1994	Wagner et al.	330	252	
	AG	5,394,159	02/1995	Schneider et al.	343	15	
	AH	4,190,838	02/1980	Kemp	343	15	
	AI	5,511,090	04/1996	Denton et al.	373	205	
	AJ						
	AK						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation Yes No
	AL	0 172 445 A1	07/1985	EPO			
	AM	0 682 382 A2	04/1995	EPO			
	AN	0 682 382 A3	05/1995	EPO			
	AO	DE 3212876 A1	04/1983	Germany			
	AP	0 616 429 A1	01/1994	EPO			
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR	N.J. Woods et al., "One micrometer scale self-aligned cobalt disilicide Schottky barrier diodes", ELECTRONICS LETTERS, IEE Stevenage, GB, Vol. 31, No. 21, Oct. 1995, pages 1878-1880					
	AS	Shenai Krishna, "Characteristics of LPCVD WSi2N-Si Schottky Contacts", IEEE ELECTRON DEVICE LETTERS, U.S. IEEE INC. N.Y., Vol. 12, No. 4, April 1991, pages 169-171					
	AT						
EXAMINER				DATE CONSIDERED			
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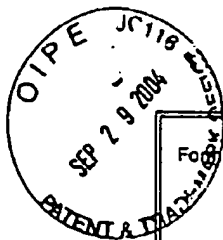
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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				ATTY. DOCKET NO. M140-273		SERIAL NO. 09/502,693	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.			
				FILING DATE February 11, 2000		GROUP 2687	
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
~	AA 5,640,151	06/17/97	Reis et al.	340	825.34		
~	AB 4,384,288	05/17/83	Walton	340	825.34		
✓	AC 4,514,731	04/30/85	Fulch et al.	340	825.08		
~	AD 4,868,908	09/19/89	Pless et al.	323	267		
✓	AE 5,103,156	04/07/92	Jones et al.	320	35		
~	AF 5,406,297	04/11/95	Caswell et al.	343	741		
~	AG 5,485,520	01/16/96	Chen et al.	380	24		
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	AI						
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FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AL						
	AM						
	AN						
	AO						
	AP						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR						
	AS						
	AT						
EXAMINER <i>Phil J. [Signature]</i>				DATE CONSIDERED 2/2/2005			
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI40-273		SERIAL NO. 09/502,693	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT: Micron Technology, Inc. <b>RECEIVED</b>			
					FILING DATE February 11, 2000		OCT 8 2004 GROUP 8 3602-2084 Technology Center 2000	
U.S. PATENT DOCUMENTS								
Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
h	AA	4,843,354	06/1989	Fuller et al.	333	81		
~	AB	5,448,770	09/1995	Hietala et al.	455	125		
~	AC	5,696,025	12/1997	Violette et al.	437	175		
~	AD	5,741,462	04/1998	Nova et al.	422	68.1		
~	AE	3,694,776	09/1972	Linder	333	17		
~	AF	3,921,094	11/1975	Schaible	331	1		
~	AG	5,121,407	06/1992	Partya et al.	375	1		
~	AH	5,334,951	08/1994	Hogeboom	331	1		
~	AJ	5,705,947	01/1998	Jeong	327	270		
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
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	AJ							
	AK							
	AL							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AM							
	AM							
	AM							
	AO							
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EXAMINER		DATE CONSIDERED						
~		2/2/2005						
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Sheet 1 of 1

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M140-273		SERIAL NO. 09/502,693	
<b>LIST OF ART CITED BY APPLICANT</b> (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.		FILING DATE February 11, 2000	
				GROUP 2687			
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
~	AA 5,361,403	11/1994	Dent	455	74		
~	AB 5,423,074	06/1995	Dent	455	74		
~	AC 4,783,646	11/1988	Mitsuzaki	340	572		
~	AD 5,072,194	12/1991	Chevallier	330	260		
~	AE 5,300,896	04/1994	Suesserman	330	260		
~	AF 5,365,192	11/1994	Wagner et al.	330	252		
~	AG 5,394,159	02/1995	Schneider et al.	343	700		
~	AH 4,190,838	02/1980	Kemp	343	18		
~	AI 5,511,090	04/1996	Denton et al.	375	205		
	AJ						
	AK						
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
~	AL 0 172 445 A1	07/1985	EPO				x
~	AM 0 682 382 A2	04/1995	EPO			x	
~	AN 0 682 382 A3	05/1995	EPO			x	
	AO 05-3212876 A1	04/1983	Germany				x
	AP 0-646-429-AT	01/1991	EPO				x
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
~	AR	N.J. Woods et al., "One micrometer scale self-aligned cobalt disilicide Schottky barrier diodes", ELECTRONICS LETTERS, IEE Stevenage, GB, Vol. 31, No. 21, Oct. 1995, pages 1878-1880					
~	AS	Shenai Krishna, "Characteristics of LPCVD WS12/N-Si Schottky Contacts", IEEE ELECTRONIC DEVICES LETTERS, US, IEEE INC. N.Y., Vol. 12 No. 4, April 1991, pages 169-171					
	AT						
EXAMINER P. S. Subrah				DATE CONSIDERED 6/18/07			
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